

Ain Shams University University Collage of Women for Arts, Science and Education

Study the Effect of Ga content on the physical properties of thermally evaporated (Ge_{25-x}Ga_x Se₇₅) thin films

A Thesis
Submitted To University Collage of Women For Arts,
Science and Education - Ain Shams University
For The Ph.D Degree in (Physics)

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STUDY THE EFFECT OF GA CONTENT ON THE PHYSICAL PROPERTIES OF THERMALLY EVAPORATED (Ge_{25-x}Ga_xSe₇₅) THIN FILMS

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Date of Research: //2016

Approval Stamp: Date of Approval: // 2016

Approval of Faculty Council. Approval of University Council.

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TITLE OF THESIS : STUDY THE EFFECT OF Ga

CONTENT ON THE PHYSICAL PROPERTIES OF THERMALLY EVAPORATED (Ge_{25-x}Ga_xSe₇₅)

THIN FILMS

SCIENTIFIC DEGREE : DOCTOR OF PHILOSOPHY IN

PHYSICS (SOLID STATE).

DEPARTMENT : PHYSICS

NAME OF FACULTY : UNIVERSITY COLLAGE OF

WOMEN FOR ARTS, SCIENCE

AND EDUCATION.

UNIVERSITY : AIN SHAMS.

B.SC. GRADUATION DATE : 2005.

M.SC. GRADUATION DATE : 2011.

PH.D GRADUATION DATE : 2016.





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Dedication





Dedication

To

My father and mother Strong and gentle souls who taught me to trust in Allah, believe in hard work and for being my first teachers

My brothers and sister For supporting and encouraging me to believe in myself

My wife and kids Thanks for your continuous support and encouragement





Acknowledgment





ACKNOWLEDGEMENT

First and foremost-unlimited thanks are due to **ALLAH** the beneficent and Merciful.

I wish to express my supreme gratitude and cordial thanks to Prof. Dr. **Siham Mahmoud Mohamed Salem**, Professor of Solid State Physics, Electron Microscope and Thin Films Department, Physics Division, National Research Centre (NRC) for planning this work and her sincere efforts for helping me to finish this work in its final form.

My deepest appreciation to Prof. Dr. Massarat Bakr Seddik Osman, Prof. of Solid State Physics, Physics Department, University Collage of Women for Arts, Science and Education, Ain Shams University for her valuable advice, sincere help, powerful support and kind supervision.

I would like to express my special thanks and gratitude to Prof. Dr. **Abd El-Rahman Salem**, Prof. of Solid State Physics, Electron Microscope and Thin Films Department, Physics Division, National Research Centre, for constructive discussion, extraordinary assistance and guidance throughout this thesis.

I wish to express my gratitude to the **Soul of** the late Prof. Dr. **Abd El Hamid El-Said Eid** Prof. of Solid State Physics,

Electron Microscope and Thin Films Department, Physics Division, National Research Centre for his kind supervision through the first part of this study.

I wish to express my gratitude to the **Soul of** the Prof. Dr. **Mahmoud Solaiman Selim** Prof. of Solid State Physics, Electron Microscope and Thin Films Department, Physics Division, National Research Centre for his effective advices through the first part of this study.

To all **Members of Electron Microscope and Thin Films Department**, NRC and to all who helped me and made this work possible, I owe my sincere gratitude.





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